

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



# Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China









# RFG40N10, RFP40N10, RF1S40N10, RF1S40N10SM

Data Sheet

January 2002

# 40A, 100V, 0.040 Ohm, N-Channel Power MOSFETs

These are N-Channel power MOSFETs manufactured using the MegaFET process. This process, which uses feature sizes approaching those of LSI integrated circuits gives optimum utilization of silicon, resulting in outstanding performance. They were designed for use in applications such as switching regulators, switching converters, motor drivers, relay drivers and emitter switches for bipolar transistors. These transistors can be operated directly from integrated circuits.

Formerly developmental type TA9846

# **Ordering Information**

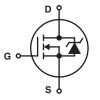
PART NUMBER	PACKAGE	BRAND
RFG40N10	TO-247	RFG40N10
RFP40N10	TO-220AB	RFP40N10
RF1S40N10	TO-262AA	F1S40N10
RF1S40N10SM	TO-263AB	F1S40N10

NOTE: When ordering, use the entire part number. Add the suffix, 9A, to obtain the TO-263AB variant in tape and reel, i.e. RF1S40N10SM9A.

#### **Features**

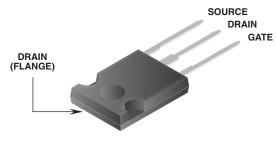
- 40A, 100V
- $r_{DS(ON)} = 0.040\Omega$
- · UIS Rating Curve
- · SOA is Power Dissipation Limited
- 175°C Operating Temperature
- · Related Literature
  - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

# Symbol



# Packaging

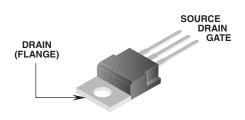
#### JEDEC STYLE TO-247



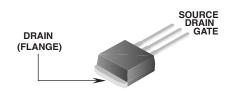
JEDEC TO-263AB



#### JEDEC TO-220AB



**JEDEC TO-262AA** 



# RFG40N10, RFP40N10, RF1S40N10, RF1S40N10SM

# **Absolute Maximum Ratings** $T_C = 25^{\circ}C$ , Unless Otherwise Specified

	RFG40N10, RFP40N10, RF1S40N10, RF1S40N10SM	UNITS
Drain to Source Breakdown Voltage (Note 1)	100	V
Drain to Gate Voltage ( $R_{GS} = 1M\Omega$ ) (Note 1)	100	V
Gate to Source Voltage	±20	V
Drain Current Continuous (Figure 2)	40 100	A A
Pulsed Avalanche RatingEAS	Figures 4, 12, 13	
Power Dissipation	160 1.07	W W/ <sup>o</sup> C
Operating and Storage Temperature	-55 to 175	°C
Maximum Temperature for Soldering  Leads at 0.063in (1.6mm) from case for 10s	300 260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

#### NOTES:

- 1.  $T_J = 25^{\circ}C$  to  $150^{\circ}C$ .
- 2. Repetitive Rating: pulse width limited by maximum junction temperature.

#### **Electrical Specifications** $T_C = 25^{\circ}C$ , Unless Otherwise Specified

PARAMETER	SYMBOL	TEST C	ONDITIONS	MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	BV <sub>DSS</sub>	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V (Figure 9)		100	-	-	V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}$ , $I_D = 250\mu A$ (Figure 8)		2	-	4	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 80V,	T <sub>C</sub> = 25°C	-	-	1	μΑ
		$V_{GS} = 0V$ $T_{C} = 150^{\circ}C$	-	-	50	μΑ	
Gate to Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±20V		-	-	±100	nA
Drain to Source On Resistance	r <sub>DS(ON)</sub>	I <sub>D</sub> = 40A, V <sub>GS</sub> = 10V (Figure 7)		-	-	0.040	Ω
Turn-On Time	t <sub>ON</sub>	$V_{DD} = 50V, I_{D} = 20A,$ $R_{L} = 2.5\Omega, V_{GS} = 10V, R_{GS} = 4.2 \Omega$ (Figure 11)		-	-	80	ns
Turn-On Delay Time	t <sub>d(ON)</sub>			-	17	-	ns
Rise Time	t <sub>r</sub>			-	30	-	ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>			-	42	-	ns
Fall Time	t <sub>f</sub>			-	20	-	ns
Turn-Off Time	t <sub>OFF</sub>			-	-	100	ns
Total Gate Charge	Q <sub>g(TOT)</sub>	V <sub>GS</sub> = 0V to 20V	V <sub>DD</sub> = 80V,	-	-	300	nC
Gate Charge at 10V	Q <sub>g(10)</sub>	V <sub>GS</sub> = 0V to 10V	$I_D = 40A,$ $R_L = 2.0\Omega$ (Figures 11)	-	-	150	nC
Threshold Gate Charge	Q <sub>g(TH)</sub>	V <sub>GS</sub> = 0V to 2V		-	-	7.5	nC
Thermal Resistance Junction to Case	$R_{\theta JC}$			-	-	0.94	°C/W
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	R <sub>θJA</sub> TO-247 TO-220AB and TO-263AB		-	-	30	°C/W
				-	-	62	°C/W

#### **Source to Drain Diode Specifications**

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	$V_{SD}$	I <sub>SD</sub> = 40A		-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>	$I_{SD} = 40A$ , $dI_{SD}/dt = 100A/\mu s$	-	-	200	ns

# Typical Performance Curves Unless Otherwise Specified

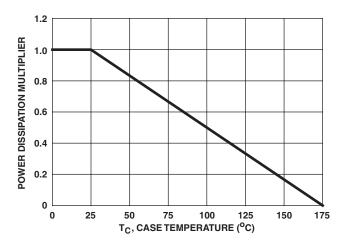


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

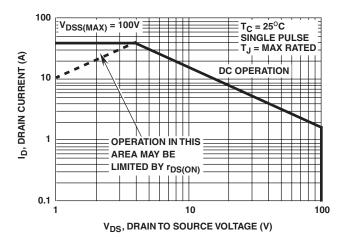


FIGURE 3. FORWARD BIAS SAFE OPERATING AREA

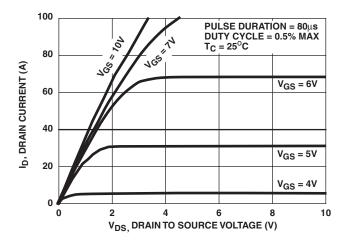


FIGURE 5. SATURATION CHARACTERISTICS

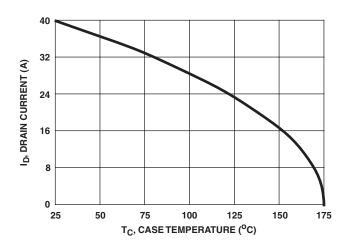
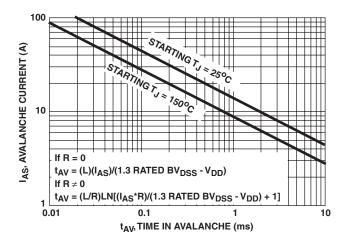


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE



NOTE: Refer to application notes AN9321 and AN9322.

FIGURE 4. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

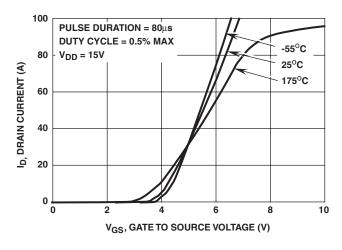


FIGURE 6. TRANSFER CHARACTERISTICS

#### Typical Performance Curves Unless Otherwise Specified (Continued)

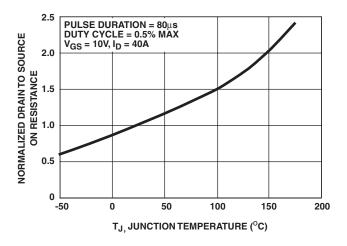


FIGURE 7. NORMALIZED DRAIN TO SOURCE ON

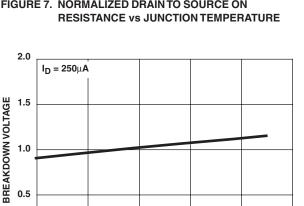


FIGURE 9. NORMALIZED DRAINTO SOURCE BREAKDOWN **VOLTAGE vs JUNCTION TEMPERATURE** 

T<sub>J.</sub> JUNCTION TEMPERATURE (°C)

100

150

200

50

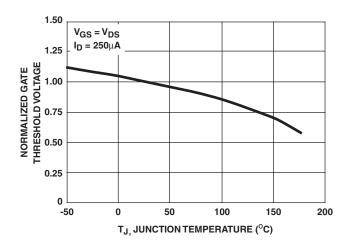


FIGURE 8. NORMALIZED GATE THRESHOLD VOLTAGE vs **JUNCTION TEMPERATURE** 

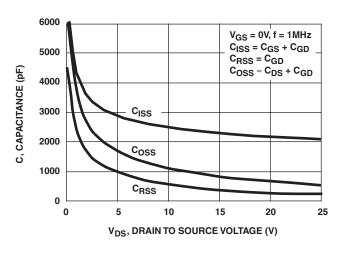
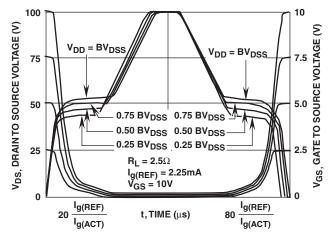


FIGURE 10. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Application Notes AN7254 and AN7260.

FIGURE 11. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT GATE CURRENT

NORMALIZED DRAIN TO SOURCE

0

-50

# Test Circuits and Waveforms

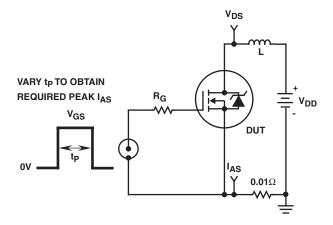


FIGURE 12. UNCLAMPED ENERGY TEST CIRCUIT

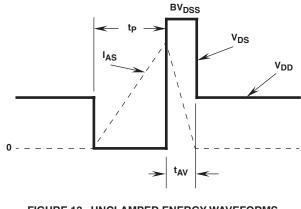


FIGURE 13. UNCLAMPED ENERGY WAVEFORMS

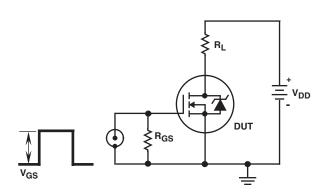


FIGURE 14. SWITCHING TIME TEST CIRCUIT

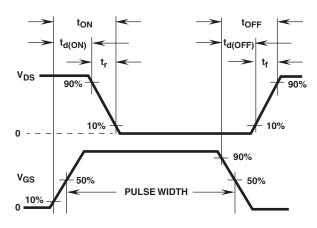


FIGURE 15. RESISTIVE SWITCHING WAVEFORMS

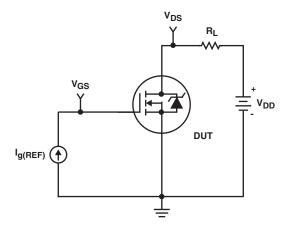


FIGURE 16. GATE CHARGE TEST CIRCUIT

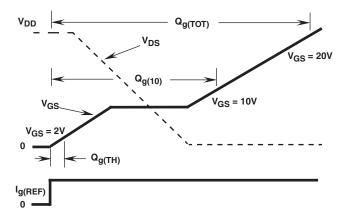


FIGURE 17. GATE CHARGE WAVEFORMS

#### **TRADEMARKS**

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

FAST ® SMART START™  $VCX^{TM}$ ACEx™ OPTOLOGIC™ STAR\*POWER™ FASTr™ Bottomless™ OPTOPLANAR™ Stealth™ CoolFET™ FRFET™ PACMAN<sup>TM</sup> SuperSOT™-3 CROSSVOLT™ GlobalOptoisolator™ POP™ SuperSOT™-6 DenseTrench™ GTO™ Power247™  $\mathsf{HiSeC^{\mathsf{TM}}}$ SuperSOT™-8 DOME™ PowerTrench® SyncFET™ ISOPLANAR™ EcoSPARK™ QFET™ TinyLogic™ E<sup>2</sup>CMOS<sup>TM</sup> LittleFET™  $OS^{TM}$ EnSigna™ MicroFET™ TruTranslation™ QT Optoelectronics™ MicroPak™ UHC™ **FACT™** Quiet Series™ UltraFET® FACT Quiet Series™ MICROWIRE™ SILENT SWITCHER®

STAR\*POWER is used under license

#### **DISCLAIMER**

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS. NOR THE RIGHTS OF OTHERS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

#### PRODUCT STATUS DEFINITIONS

#### **Definition of Terms**

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

Rev. H4